

MM2716E 16,384-Bit (2048 × 8) UV Erasable PROM

Extended Temperature Range

General Description

The MM2716E is a high speed 16k UV erasable and electrically reprogrammable EPROM ideally suited for applications where fast turn-around and pattern ex-

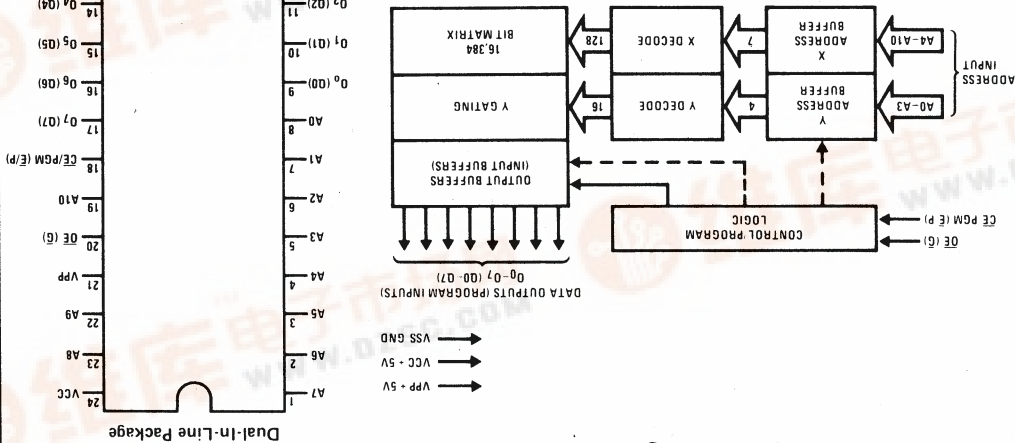
The MM2716E is packaged in a 24-pin dual-in-line package with transparent lid. The transparent lid allows the user to expose the chip to ultraviolet light to erase the bit pattern. A new pattern can then be written into the device by following the programming procedure.

This EPROM is fabricated with the reliable, high volume, time proven, N-channel silicon gate technology.

Features

- -40°C to +85°C
- 2048 × 8 organization
- 550 mW max active power, 137.5 mW max standby power
- Low power during programming
- Access time — 450 ns
- Single 5V ±10% power supply
- Static—no clocks required
- Inputs and outputs TTL compatible during both read and program modes
- TRI-STATE® output

Block and Connection Diagrams*



Pin Connection During Read or Program

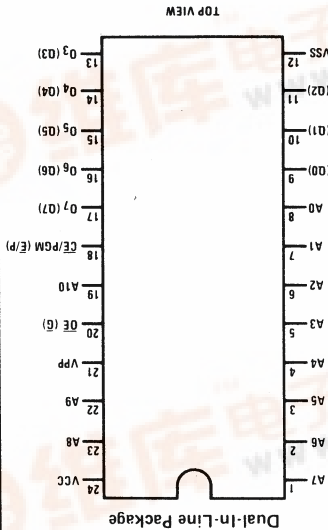
MODE		PIN NAME/NUMBER	
CE/PGM (E/P)	18	OE (G)	20
VPP	21	VCC	24
Read	VIL	DO UT	5
Pulsed VIL to VIH	VIH		25
Program			5
		DIN	

*Symbols in parentheses are proposed industry standard

5-18

Pin Names

Order Number MM2716QE
See NS Package J24CQ



A0-A10 Address Inputs
Q0-Q7 (Q0-Q7) Data Outputs
CE/PGM (E/P) Chip Enable/Program
OE (G) Output Enable
VPP Read 5V, Program 25V
VCC Power (5V)
VSS Ground

Note 1: "AT" Temperature provides con
Note 2: Typ
Note 3: VPP
Note 4: Outp
Note 5: Capa

SYMBOL
CI
CO

Capacitance
T_A = 25°C

ALTERNATE
SYM
T_A = -40°C

AC Characteristic

VOL

VOH

VIH

VIL

ICC2

ICC1

I_{PP1}

I_{LO}

I_{LI}

SYMBOL

DC Operating

T_A = -40°C

READ

PDF

PDF

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Absolute Maximum Ratings (Note 1)

Temperature Under Bias	−50°C to +100°C	All Input or Output Voltages with Respect to VSS (except VPP)	6V to −0.3V
Storage Temperature	−65°C to +125°C	Power Dissipation	1.5 W
VPP Supply Voltage with Respect to VSS	26.5V to −0.3V	Lead Temperature (Soldering, 10 seconds)	300°C

READ OPERATION (Note 2)**DC Operating Characteristics**

$T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{PP} = V_{CC} \pm 0.6\text{V}$ (Note 3), $V_{SS} = 0\text{V}$, unless otherwise noted.

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
ILI	Input Current	$V_{IN} = 5.5\text{V}$ or $V_{IN} = V_{IL}$			10	μA
ILO	Output Leakage Current	$V_{OUT} = 5.5\text{V}$, $\overline{\text{CE}}/\text{PGM} = 5\text{V}$			10	μA
IPP1	VPP Supply Current	$V_{PP} = 6.1\text{V}$			5	mA
ICC1	VCC Supply Current (Standby)	$\overline{\text{CE}}/\text{PGM} = V_{IH}$, $\overline{\text{OE}} = V_{IL}$		10	25	mA
ICC2	VCC Supply Current (Active)	$\overline{\text{CE}}/\text{PGM} = \overline{\text{OE}} = V_{IL}$		57	100	mA
VIL	Input Low Voltage		−0.1		0.8	V
VIH	Input High Voltage		2.0		$V_{CC} + 1$	V
VOH	Output High Voltage	$I_{OH} = -400\mu\text{A}$	2.4			V
VOL	Output Low Voltage	$I_{OL} = 2.1\text{mA}$			0.45	V

AC Characteristics (Note 4)

$T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{PP} = V_{CC} \pm 0.6\text{V}$ (Note 3), $V_{SS} = 0\text{V}$, unless otherwise noted.

SYMBOL		PARAMETER	CONDITIONS	MIN	MAX	UNITS
ALTERNATE	STANDARD					
t_{ACC}	TAVQV	Address to Output Delay	$\overline{\text{CE}}/\text{PGM} = \overline{\text{OE}} = V_{IL}$		450	ns
t_{CE}	TELQV	$\overline{\text{E}}$ to Output Delay	$\overline{\text{OE}} = V_{IL}$		450	ns
t_{OE}	TGLQV	Output Enable to Output Delay	$\overline{\text{CE}}/\text{PGM} = V_{IL}$		120	ns
t_{DF}	TGHQZ	Output Enable High to Output Hi-Z	$\overline{\text{CE}}/\text{PGM} = V_{IL}$	0	100	ns
t_{OH}	TAXQX	Address to Output Hold	$\overline{\text{CE}}/\text{PGM} = \overline{\text{OE}} = V_{IL}$	0		ns
t_{OD}	TEHQZ	$\overline{\text{E}}$ to Output Hi-Z	$\overline{\text{OE}} = V_{IL}$	0	100	ns

Capacitance (Note 5)

$T_A = 25^{\circ}\text{C}$, $f = 1\text{MHz}$

SYMBOL	PARAMETER	CONDITIONS	TYP	MAX	UNITS
CI	Input Capacitance	$V_{IN} = 0\text{V}$	4	6	pF
CO	Output Capacitance	$V_{OUT} = 0\text{V}$	8	12	pF

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

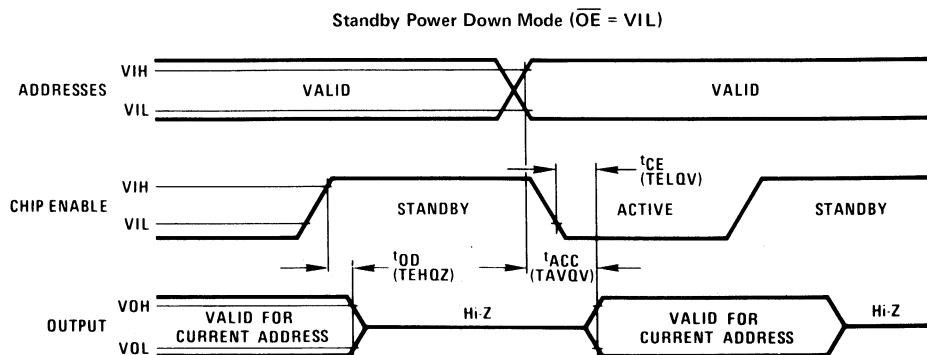
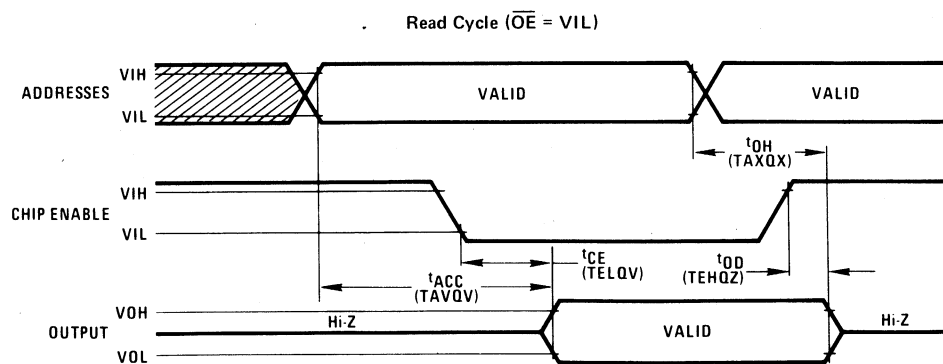
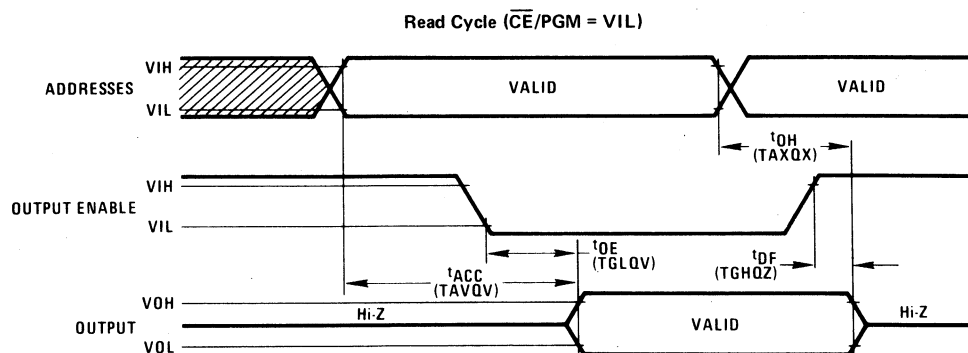
Note 2: Typical conditions are for operation at: $T_A = 25^{\circ}\text{C}$, $V_{CC} = 5\text{V}$, $V_{PP} = V_{CC}$, and $V_{SS} = 0\text{V}$.

Note 3: VPP may be connected to VCC except during program. The $\pm 0.6\text{V}$ tolerance allows a circuit to switch VPP between the read voltage and the program voltage.

Note 4: Output load: 1 TTL gate and $C_L = 100\text{pF}$. Input rise and fall times $\leq 20\text{ns}$.

Note 5: Capacitance is guaranteed by periodic testing.

Switching Time Waveforms*



DC Electrical Characteristics and Operating Conditions (Notes 1 and 2)

(T_A = 25°C ±5°C) (V_{CC} = 5V ±5%, V_{PP} = 25V ±1V)

SYMBOL	PARAMETER				UNITS
	MIN	TYP	MAX		
ILI	Input Leakage Current (Note 3)		10	μA	
VIL	Input Low Level	-0.1	0.8	V	
VIH	Input High Level	2.0	V _{CC} + 1	V	
ICC	V _{CC} Power Supply Current		100	mA	
IPP1	V _{PP} Supply Current (Note 4)		5	mA	
IPP2	V _{PP} Supply Current During Programming Pulse (Note 5)		30	mA	

AC Characteristics and Operating Conditions (Notes 1, 2, and 6)

(T_A = 25°C ±5°C) (V_{CC} = 5V ±5%, V_{PP} = 25V ±1V)

SYMBOL		PARAMETER				UNITS
ALTERNATE	STANDARD	MIN	TYP	MAX		
t _{AS}	t _{AVPH}	Address Setup Time	2			ns
t _{OS}	t _{GHPH}	<u>OE</u> Setup Time	2			ns
t _{DS}	t _{DVPH}	Data Setup Time	2			ns
t _{AH}	t _{PLAX}	Address Hold Time	2			ns
t _{OH}	t _{PLGX}	<u>OE</u> Hold Time	2			ns
t _{DH}	t _{PLDX}	Data Hold Time	2			ns
t _{DF}	t _{GHOZ}	Chip Disable to Output Float Delay (Note 4)	0		100	ns
t _{CE}	t _{GLOV}	Chip Enable to Output Delay (Note 4)			120	ns
tp _W	TPHPL	Program Pulse Width	45	50	55	ms
tp _R	TPH1PH2	Program Pulse Rise Time	5			ns
tp _F	TPL2PL1	Program Pulse Fall Time	5			ns

Note 1: V_{CC} must be applied at the same time or before V_{PP} and removed after or at the same time as V_{PP}. To prevent damage to the device it must not be inserted into a board with power applied.

Note 2: Care must be taken to prevent overshoot of the V_{PP} supply when switching to +25V.

Note 3: 0.45V ≤ V_{IN} ≤ 5.25V.

Note 4: $\overline{CE}/PGM = V_{IL}$, V_{PP} = V_{CC} + 0.6V.

Note 5: V_{PP} = 26V.

Note 6: Transition times ≤ 20 ns unless noted otherwise.

Functional Description

DEVICE OPERATION

The MM2716E has 3 modes of operation in the normal system environment. These are shown in Table I.

Read Mode

The MM2716E read operation requires that $\overline{OE} = \text{VIL}$, $\overline{CE}/\text{PGM} = \text{VIL}$ and that addresses A0–A10 have been stabilized. Valid data will appear on the output pins after tACC, tOE, tCE times (see Switching Time Waveforms) depending on which is limiting.

Deselect Mode

The MM2716E is deselected by making $\overline{OE} = \text{VIL}$. This mode is independent of $\overline{CE}/\text{PGM}$ and the condition of the addresses. The outputs are Hi-Z when $\overline{OE} = \text{VIL}$. This allows OR'ing 2 or more MM2716Es for memory expansion.

PROGRAMMING

The MM2716E is shipped from National completely erased. All bits will be at a "1" level (output high) in this initial state and after any full erasure. Table II shows the 3 programming modes.

TABLE I. OPERATING MODES (VCC = VPP = 5V)

MODE		Read	Deselect	Standby
PIN NAME/NUMBER		<u>CE</u> /PGM (E/P) 18	VIL Don't Care VIL	VIL Don't Care Hi-Z
OUTPUTS	9–11, 13–17	<u>OE</u> (G) 20	VIL DOUT Hi-Z	Hi-Z

TABLE II. PROGRAMMING MODES (VCC = 5V)

MODE		Program	Program Verify	Program Inhibit
CE/pGM (E/p) 18		Pulsed VIL to VIH	VIL VIL VIL	VIL
OE (G) 20		VIH	25	25
VPP		21	25	25
OUTPUTS 0		9-11, 13-17	DIN	DOUT HI-Z
PIN NAME/NUMBER				

*Symbols in parentheses are proposed industry standard

ERASING

program a unit while inhibiting the program pulse to a unit will keep it from being programmed and keeping OE = VIH will put its outputs in the Hi-Z state.

The MM2716E is erased by exposure to high intensity ultraviolet light through the transparent window. This exposure discharges the floating gate to its initial state through induced photo current. It is recommended that the MM2716E be kept out of direct sunlight. The UV content of sunlight may cause a partial erasure of some bits in a relatively short period of time. Direct sunlight (any intense light) can cause temporary functional failure due to generation of photo current. Extended exposure to room level fluorescent lighting will also cause erasure. An opaque coating (paint, tape, label, etc.) should be placed over the package window if this product is to be operated under these lighting conditions.

An ultraviolet source of 2537 Å yielding a total integrated dosage of 15 watt-seconds/cm² is required. This will erase the part in approximately 15 to 20 minutes if a UV lamp with a 12,000 μW/cm² power rating is used. The MM2716E to be erased should be placed 1 inch away from the lamp and no filters should be used.

An erasure system should be calibrated periodically. The distance from lamp to unit should be maintained at 1 inch. The erasure time is doubled the erasure time goes up by a factor of 4). Lamps lose intensity as they age. When a lamp is changed, the distance is checked to make certain full erasure is occurring. Incomplete erasure will cause symptoms that can be misleading. Programmers, components, and system designs have been erroneously suspected when incomplete erasure was the basic problem.

The MM2716E is programmed by introducing "0"s into the desired locations. This is done 8 bits (a byte) at a time. Any individual address, a sequence of addresses, or addresses chosen at random may be programmed. Any or all of the 8 bits associated with an address location may be programmed with a single program pulse applied to the chip enable pin. All input voltage levels, including the program pulse on chip-enable are TTL compatible. The programming sequence is:

With VPP = 25V, VCC = 5V, OE = VIH and CE/PGM = VIL, an address is selected and the desired data word is applied to the output pins. (VIL = "0" and VIH = "1" for both address and data.) After the address and data signals are stable the program pin is pulsed from VIL to VIH with a pulse width between 45 ns and 55 ns.

Multiple pulses are not needed but will not cause device damage. No pins should be left open. A high level (VIH or higher) *must not* be maintained longer than tPW(MAX) on the program pin during programming. MM2716Es may be programmed in parallel with the same data in this mode.

Program Verify Mode

The programming of the MM2716E may be verified either 1 word at a time during the programming (as shown in the timing diagram) or by reading all of the words out at the end of the programming sequence. This can be done with VPP = 25V (or 5V) in either case.

Program Inhibit Mode

The program inhibit mode allows programming several MM2716Es simultaneously with different data for each one by controlling which ones receive the program pulse. All similar inputs of the MM2716E may be paralleled. Pulsing the program pin (from VIL to VIH) will